

Notice of References Cited	Application/Control No. 10/754,321		Applicant(s)/Patent Under Reexamination MAK ET AL.	
	Examiner DuyVu n. Deo		Art Unit 1765	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,891,627	05-2005	Levy et al.	356/625
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NON-PATENT DOCUMENTS

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